

# MICROSCOPY TODAY

DECEMBER 2000

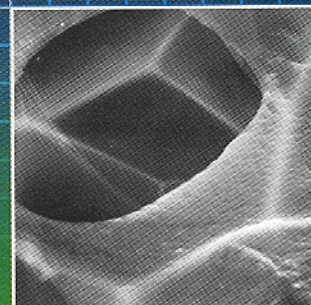
ISSUE #00-10



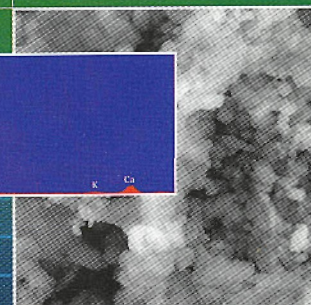
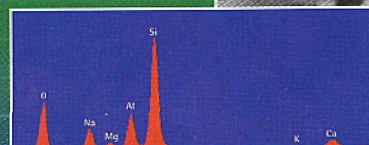


# Ultra-high resolution FESEM Plus Variable Pressure?

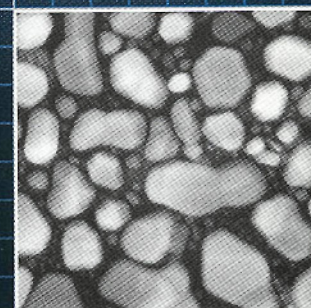
## Have it all – with LEO



Styrofoam, uncoated, 30kV, 1,000x,  
chamber pressure 35 Pa, VPSE detector



Lead oxide, uncoated, 21kV, 10,000x,  
chamber pressure 34 Pa, VPSE detector



Gold on carbon, 30kV, 50,000x,  
chamber pressure 40 Pa, VPSE detector

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Market leading ultra-high resolution electron optics and Variable Pressure  
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